

1-MHz, Micro-Power, Low-Noise, RRIO, 1.8-V CMOS **OPERATIONAL AMPLIFIER** Precision Value Line Series

Check for Samples: OPA313, OPA2313, OPA4313

FEATURES

- Low I_Q: 50 µA/ch
- Wide Supply Range: 1.8 V to 5.5 V
- Low Noise: 25 nV/VHz at 1 kHz
- Gain Bandwidth: 1 MHz
- Low Input Bias Current: 0.2 pA
- Low Offset Voltage: 0.5 mV
- **Unity-Gain Stable**
- **Internal RF/EMI Filter**
- **Extended Temperature Range:** -40°C to +125°C

APPLICATIONS

- **Battery-Powered Instruments:**
 - Consumer, Industrial, Medical
 - Notebooks, Portable Media Players
- Sensor Signal Conditioning:
 - Loop-Powered
 - Notebooks, Portable Media Players
- Wireless Sensors:
 - Home Security
 - Remote Sensing
 - Wireless Metering

DESCRIPTION

The OPA313 family of single-, dual-, and quadchannel op amps represents a new generation of lowcost, general purpose, micro-power operational amplifiers. Featuring rail-to-rail input and output swings, and low quiescent current (50 µA, typ) combined with a wide bandwidth of 1 MHz and very low noise (25 nV/ \sqrt{Hz} at 1 kHz) makes this family very attractive for a variety of battery-powered applications that require a good balance between cost and performance. The low input bias current supports those op amps to be used in applications with megaohm source impedances.

The robust design of the OPA313 devices provides ease-of-use to the circuit designer: unity-gain stability with capacitive loads of up to 150 pF, integrated RF/EMI rejection filter, no phase reversal in overdrive conditions, and high electrostatic discharge (ESD) protection (4-kV HBM).

These devices are optimized for operation at voltages as low as +1.8 V (±0.9 V) and up to +5.5 V (±2.75 V), and are specified over the extended temperature range of -40°C to +125°C.

The OPA313 (single) is available in both SC70-5 and SOT23-5 packages. The OPA2313 (dual) is offered in SO-8, MSOP-8, and DFN-8 packages. The quadchannel OPA4313 is offered in a TSSOP-14 package.



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OPA313 OPA2313 OPA4313



SBOS649C-SEPTEMBER 2012-REVISED MARCH 2013

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

PACKAGE INFORMATION (1)						
PRODUCT	PACKAGE-LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	PACKAGE MARKING		
004040	SC70-5	DCK	-40°C to +125°C	SIE		
OPA313	SOT23-5	DBV	-40°C to +125°C	SIF		
	SO-8	D	-40°C to +125°C	OP2313		
OPA2313	MSOP-8	DGK	-40°C to +125°C	OUSS		
	DFN-8	DRG	-40°C to +125°C	SDY		
OPA4313	TSSOP-14	PW	-40°C to +125°C	OPA4313		

For the most current package and ordering information, see the Package Option Addendum at the end of this document, or visit the (1)device product folder at www.ti.com.

ABSOLUTE MAXIMUM RATINGS⁽¹⁾

Over operating free-air temperature range, unless otherwise noted.

		OPA313, OPA2313, OPA4313	UNIT
Supply voltage		7	V
O'ment in a la	Voltage ⁽²⁾	(V–) – 0.5 to (V+) + 0.5	V
Signal input terminals	Current ⁽²⁾	±10	mA
Output short-circuit ⁽³⁾		Continuous	mA
Operating temperature, T _A		-40 to +150	°C
Storage temperature, T _{stg}		-65 to +150	°C
Junction temperature, T _J		+150	°C
	Human body model (HBM)	4000	V
ESD rating	Charged device model (CDM)	1000	V
	Machine model (MM)	200	V

(1) Stresses above these ratings may cause permanent damage. Exposure to absolute maximum conditions for extended periods may degrade device reliability. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those specified is not supported.

Input terminals are diode-clamped to the power-supply rails. Input signals that can swing more than 0.5 V beyond the supply rails should (2)be current limited to 10 mA or less.

Short-circuit to ground, one amplifier per package. (3)



ELECTRICAL CHARACTERISTICS: +5.5 V⁽¹⁾

At T_A = +25 °C, R_L = 10 k Ω connected to V_S / 2, and V_{CM} = V_{OUT} = V_S / 2, unless otherwise noted.

			OPA313, OPA2313, OPA4313			
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFFSET \	/OLTAGE				÷	
V _{OS}	Input offset voltage			0.5	2.5	mV
dV _{OS} /dT	vs Temperature	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		2		μV/°C
PSRR	vs power supply	$T_A = -40^{\circ}C$ to $+125^{\circ}C$	74	90		dB
	Channel separation, dc	At dc		10		μV/V
INPUT VO	DLTAGE RANGE					
V _{CM}	Common-mode voltage range	No phase reversal, rail-to-rail input	(V−) − 0.2		(V+) + 0.2	V
CMRR	Common-mode rejection ratio	$T_A = -40^{\circ}C$ to +125°C, (V _S -) - 0.2 V < V _{CM} < (V _S +) - 1.3 V	70	85		dB
CIVIRK	Common-mode rejection ratio	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C,$ $V_{CM} = -0.2 \text{ V to } 5.7 \text{ V}$	64	80		dB
INPUT BI	AS CURRENT				÷	
				±0.2	±10	pА
I _B	Input bias current	$T_A = -40^{\circ}C$ to $+85^{\circ}C^{(2)}$			±50	pА
		$T_A = -40^{\circ}C \text{ to } +125^{\circ}C^{(2)}$			±600	pА
				±0.2	±10	pА
l _{os}	Input offset current	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C^{(2)}$			±50	pА
		$T_A = -40^{\circ}C \text{ to } +125^{\circ}C^{(2)}$			±600	pА
NOISE					÷	
	Input voltage noise (peak-to- peak)	f = 0.1 Hz to 10 Hz		6		μV _{PF}
_	land too lite and an include a lite.	f = 10 kHz		22		nV/√F
en	Input voltage noise density	f = 1 kHz		25		nV/√F
i _n	Input current noise density	f = 1 kHz		5		fA/√H
INPUT CA	PACITANCE				÷	
<u> </u>	Differential			1		pF
C _{IN} Common-mode				5		pF
OPEN-LO	OP GAIN					
		$0.05 \text{ V} < \text{V}_{\text{O}} < (\text{V+}) - 0.05 \text{ V}, \text{ R}_{\text{L}} = 100 \text{ k}\Omega$	90	104		dB
A _{OL}	Open-loop voltage gain	$T_A = -40^{\circ}C$ to +125°C, 0.1 V < V _O < (V+) - 0.1 V	104	116	_	dB
		$0.3 \text{ V} < \text{V}_{\text{O}} < (\text{V+}) - 0.3 \text{ V}, \text{ R}_{\text{L}} = 2 \text{ k}\Omega$	100	110		dB
	Phase margin	V _S = 5.0 V, G = +1		65		degre

(1) Parameters with minimum or maximum specification limits are 100% production tested at +25°C, unless otherwise noted. Over temperature limits are based on characterization and statistical analysis.

(2) Specified by design and characterization; not production tested.



ELECTRICAL CHARACTERISTICS: +5.5 V⁽¹⁾ (continued)

At T_A = +25 °C, R_L = 10 kΩ connected to V_S / 2, and V_{CM} = V_{OUT} = V_S / 2, unless otherwise noted.

			OPA313, OPA2	313, OPA4	313	
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
FREQUEN	ICY RESPONSE					
GBW	Gain-bandwidth product	V _S = 5.0 V, C _L = 10 pF		1		MHz
SR	Slew rate	V _S = 5.0 V, G = +1		0.5		V/µs
	Cottling time	To 0.1%, $V_S = 5.0 V$, 2-V step , G = +1		5		μs
ts	Settling time	To 0.01%, V _S = 5.0 V, 2-V step , G = +1		6		μs
	Overload recovery time	V_{S} = 5.0 V, V_{IN} × Gain > V_{S}		3		μs
THD+N	Total harmonic distortion + noise ⁽³⁾	V _S = 5.0 V, V _O = 1 V _{RMS} , G = +1, f = 1 kHz	0.00	45%		
OUTPUT					1	
		$R_{L} = 100 \ k\Omega^{(4)}$		5	20	mV
	Voltage output swing from supply rails	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C, R_L = 100 \text{ k}\Omega^{(4)}$			30	mV
Vo		$R_L = 2 k\Omega^{(4)}$		75	100	mV
		$T_A = -40^{\circ}C$ to +125°C, $R_L = 2 \text{ k}\Omega$			125	mV
				±15		mA
I _{SC}	Short-circuit current	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		±12		mA
Ro	Open-loop output impedance			2300		Ω
POWER S	SUPPLY					
Vs	Specified voltage range		1.8 (±0.9)	5.5	(±2.75)	V
		I _O = 0 mA, V _S = 5.0 V		50	60	μA
lq	Quiescent current per amplifier	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C, V_S = 5.0 \text{ V}, I_O = 0 \text{ mA}$			85	μA
	Power-on time	$V_{S} = 0 V \text{ to } 5 V$, to 90% I_{Q} level		10		μs
TEMPERA	ATURE					
	Specified range		-40		+125	°C
	Operating range		-40		+150	°C
	Storage range		-65		+150	°C

(3) Third-order filter; bandwidth = 80 kHz at - 3 dB.

(4) Specified by design and characterization; not production tested.

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ELECTRICAL CHARACTERISTICS: +1.8 V⁽¹⁾

At $T_A = +25 \text{ °C}$, F	$R_{L} = 10 \ k\Omega$ connected to	$V_{\rm S}$ / 2, $V_{\rm CM} = V_{\rm S+}$ -	- 1.3 V, and V _{OUT} = "	V _S / 2, unless otherwise noted.
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			OPA313, O	PA2313, C	PA4313	
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFFSET	VOLTAGE					
V _{OS}	Input offset voltage			0.5	2.5	mV
dV _{OS} /dT	vs Temperature	$T_A = -40^{\circ}C \text{ to } +125^{\circ}C$		2		µV/°C
PSRR	vs power supply	$T_A = -40^{\circ}C$ to $+125^{\circ}C$	74	90		dB
	Channel separation, dc	At dc		10		μV/V
INPUT VC	DLTAGE RANGE				·	
V _{CM}	Common-mode voltage range	No phase reversal, rail-to-rail input	(V–) – 0.2		(V+) + 0.2	V
		$T_A = -40^{\circ}C$ to +125°C, (V _S -) - 0.2 V < V _{CM} < (V _S +) - 1.3 V	70	85		dB
CMRR	Common-mode rejection ratio	$V_{\rm S}$ = 1.8 V, $V_{\rm CM}$ = -0.2 V to +1.8 V	58	73		
		$T_A = -40^{\circ}C$ to +125°C, $V_{CM} = -0.2$ V to 1.6 V	58	70		dB
INPUT BI	AS CURRENT				·	
				±0.2	±10	pА
IB	Input bias current	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C^{(2)}$			±50	pА
		$T_A = -40^{\circ}C \text{ to } +125^{\circ}C^{(2)}$			±600	pА
				±0.2	±10	pА
los	Input offset current	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C^{(2)}$			±50	pА
		$T_A = -40^{\circ}C \text{ to } +125^{\circ}C^{(2)}$			±600	pА
NOISE			·			
	Input voltage noise (peak-to- peak)	f = 0.1 Hz to 10 Hz		6		μV_{PP}
_	land to the second second second	f = 10 kHz		22		nV/√Hz
e _n	Input voltage noise density	f = 1 kHz		25		nV/√Hz
i _n	Input current noise density	f = 1 kHz		5		fA/√Hz
INPUT CA	PACITANCE					
0	Differential			1		pF
C _{IN} Common-mode				5		pF
OPEN-LO	OP GAIN					
٨		$T_A = -40^{\circ}C$ to +125°C, 0.1 V < V _O < (V+) - 0.1 V	90	110		dB
A _{OL}	Open-loop voltage gain	$0.05 \text{ V} < \text{V}_{\text{O}} < (\text{V+}) - 0.05 \text{ V}, \text{ R}_{\text{L}} = 100 \text{ k}\Omega$	100	110		dB

(1) Parameters with minimum or maximum specification limits are 100% production tested at +25°C, unless otherwise noted. Over temperature limits are based on characterization and statistical analysis. Specified by design and characterization; not production tested.

(2)



ELECTRICAL CHARACTERISTICS: +1.8 V⁽¹⁾ (continued)

At T_A = +25 °C, R_L = 10 k Ω connected to V_S / 2, V_{CM} = V_{S+} – 1.3 V, and V_{OUT} = V_S / 2, unless otherwise noted.

			OPA313, OPA2	2313, OPA4313		
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
FREQUE	NCY RESPONSE					
GBW	Gain-bandwidth product	C _L = 10 pF		0.9		MHz
SR	Slew rate	G = +1		0.45		V/µs
		To 0.1%, $V_S = 5.0 V$, 2-V step , G = +1		5		μs
t _S	Settling time	To 0.01%, $V_S = 5.0 V$, 2-V step , $G = +1$		6		μs
	Overload recovery time	$V_{S} = 5.0 \text{ V}, V_{IN} \times \text{Gain} > V_{S}$		3		μs
THD+N	Total harmonic distortion + noise ⁽³⁾	$V_{S} = 5.0 \text{ V}, V_{O} = 1 \text{ V}_{RMS}, \text{ G} = +1, \text{ f} = 1 \text{ kHz}$	0.00	045%		
OUTPUT		·	· · ·			
		$R_{L} = 100 \ k\Omega^{(4)}$		5	15	mV
	Voltage output swing from supply rails	$T_A = -40^{\circ}C$ to +125°C, $R_L = 100 \text{ k}\Omega^{(4)}$			30	mV
Vo		$R_{L} = 2 k \Omega^{(4)}$		25	50	mV
		$T_A = -40^{\circ}C$ to +125°C, $R_L = 2 \text{ k}\Omega$			125	mV
I _{SC}	Short-circuit current			±6		mA
R _o	Open-loop output impedance			2300		Ω
POWER S	SUPPLY	·	· · ·			
Vs	Specified voltage range		1.8 (±0.9)	5	.5 (±2.75)	V
lq	Quiescent current per amplifier	I _O = 0 mA		50	60	μA
	Power-on time	$V_{S} = 0 V$ to 5 V, to 90% I_{Q} level		10		μs
TEMPERA	ATURE					
	Specified range		-40		+125	°C
	Operating range		-40		+150	°C
	Storage range		-65		+150	°C

(3) Third-order filter; bandwidth = 80 kHz at - 3 dB.

(4) Specified by design and characterization; not production tested.

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THERMAL INFORMATION: OPA313

			313		
	THERMAL METRIC ⁽¹⁾	DBV (SOT23)	DCK (SC70)	UNITS	
		5 PINS	5 PINS		
θ_{JA}	Junction-to-ambient thermal resistance	228.5	281.4		
$\theta_{JC(top)}$	Junction-to-case(top) thermal resistance	99.1	91.6		
θ_{JB}	Junction-to-board thermal resistance	54.6	59.6	2004	
Ψ _{JT}	Junction-to-top characterization parameter	7.7	1.5	°C/W	
Ψјв	Junction-to-board characterization parameter	53.8	58.8		
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance	N/A	N/A		

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

THERMAL INFORMATION: OPA2313

			OPA2313			
	THERMAL METRIC ⁽¹⁾	D (SO)	DGK (MSOP)	DRG (DFN)	UNITS	
		8 PINS	8 PINS	8 PINS	1	
θ_{JA}	Junction-to-ambient thermal resistance	138.4	191.2	53.8		
θ _{JC(top)}	Junction-to-case(top) thermal resistance	89.5	61.9	69.2	7	
θ_{JB}	Junction-to-board thermal resistance	78.6	111.9	20.1	°C/W	
ψ_{JT}	Junction-to-top characterization parameter	29.9	5.1	3.8	°C/W	
Ψ_{JB}	Junction-to-board characterization parameter	78.1	110.2	20.0]	
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance	N/A	N/A	11.6	7	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.

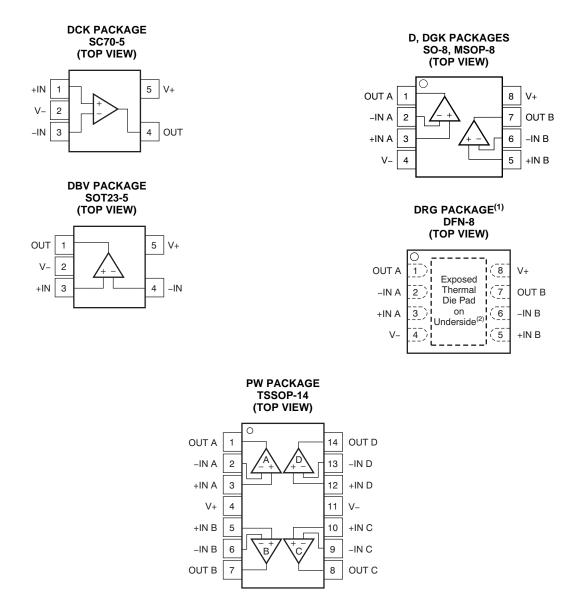
THERMAL INFORMATION: OPA4313

		OPA4313	
	THERMAL METRIC ⁽¹⁾	PW (TSSOP)	UNITS
		14 PINS	
θ _{JA}	Junction-to-ambient thermal resistance	121.0	
θ _{JC(top)}	Junction-to-case(top) thermal resistance	49.4	
θ_{JB}	Junction-to-board thermal resistance	62.8	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	5.9	°C/VV
Ψ _{JB}	Junction-to-board characterization parameter	62.2	
$\theta_{JC(bottom)}$	Junction-to-case(bottom) thermal resistance	N/A	

(1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.



PIN CONFIGURATIONS



(1) Pitch: 0,65 mm.

(2) Connect thermal pad to V–. Pad size: 1,8 mm × 1,5 mm.

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TYPICAL CHARACTERISTICS

Open-Loop Gain and Phase vs FrequencyFigure 1Open-Loop Gain vs TemperatureFigure 2Quiescent Current vs Supply VoltageFigure 3Quiescent Current vs TemperatureFigure 6Offset Voltage Production DistributionFigure 6Offset Voltage vs Common-Mode Voltage (Maximum Supply)Figure 7Offset Voltage vs Common-Mode Voltage (Maximum Supply)Figure 7Offset Voltage vs TemperatureFigure 8CMRR and PSRR vs Frequency (RTI)Figure 9CMRR and PSR vs TemperatureFigure 100.1-Hz to 10-Hz Input Voltage Noise (55 V)Figure 12Input Voltage Noise Spectral Density vs Frequency (1.8 V, 5.5 V)Figure 13Input Voltage Noise vs Common-Mode Voltage (5.5 V)Figure 14Open-Loop Output Impedance vs FrequencyFigure 15Maximum Output Voltage vs Frequency and Supply VoltageFigure 16Output Voltage Noise vs Common-Mode Voltage (5.5 V)Figure 16Output Voltage Noise vs Common-Mode Voltage (5.5 V)Figure 13Input Voltage Noise vs Common-Mode Voltage (5.5 V)Figure 14Open-Loop Output Impedance vs FrequencyFigure 16Output Voltage vs Frequency ond Supply VoltageFigure 16Output Voltage Sing vs Output Current (over Temperature)Figure 18Closed-Loop Gain vs Frequency, G = 1, -1, 10 (1.8 V)Figure 20Phase Margin vs Capacitive LoadFigure 21Small-Signal Step Response, Noninverting (1.8 V)Figure 22Small-Signal Step Response, Noninverting (1.8 V)Figure 23Large-Signal Step Response, Noninverting (1.8 V) <th>TITLE</th> <th>FIGURE</th>	TITLE	FIGURE
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TYPICAL CHARACTERISTICS

At T_A = +25 °C, V_S = 5 V, R_L = 10 k Ω connected to V_S / 2, and V_{CM} = V_{OUT} = V_S / 2, unless otherwise noted.

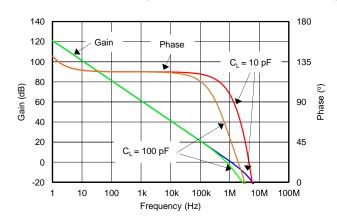
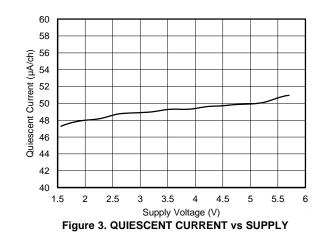
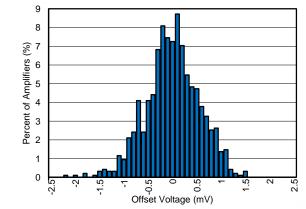


Figure 1. OPEN-LOOP GAIN AND PHASE vs FREQUENCY







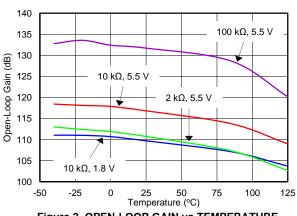
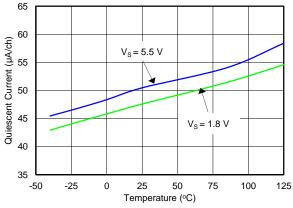


Figure 2. OPEN-LOOP GAIN vs TEMPERATURE





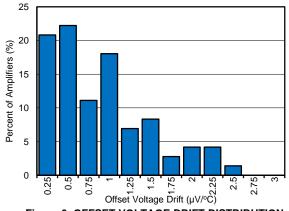


Figure 6. OFFSET VOLTAGE DRIFT DISTRIBUTION



OPA313 OPA2313 OPA4313 SBOS649C – SEPTEMBER 2012 – REVISED MARCH 2013



TYPICAL CHARACTERISTICS (continued)



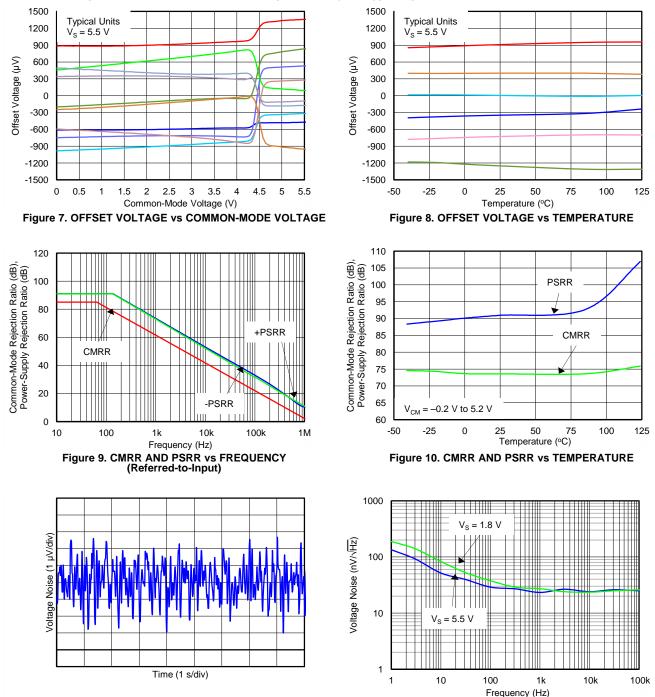
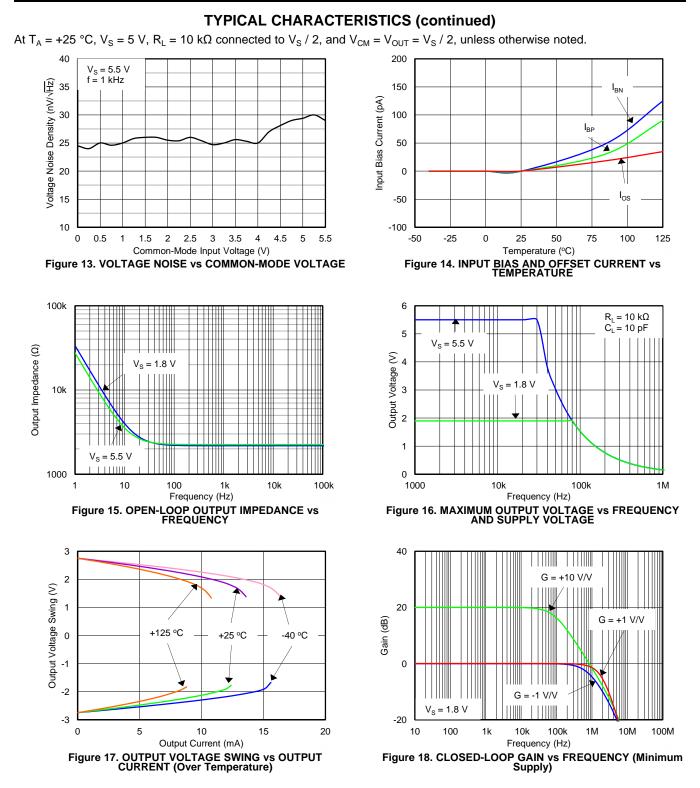


Figure 12. INPUT VOLTAGE NOISE SPECTRAL DENSITY vs FREQUENCY

Figure 11. 0.1-Hz TO 10-Hz INPUT VOLTAGE NOISE







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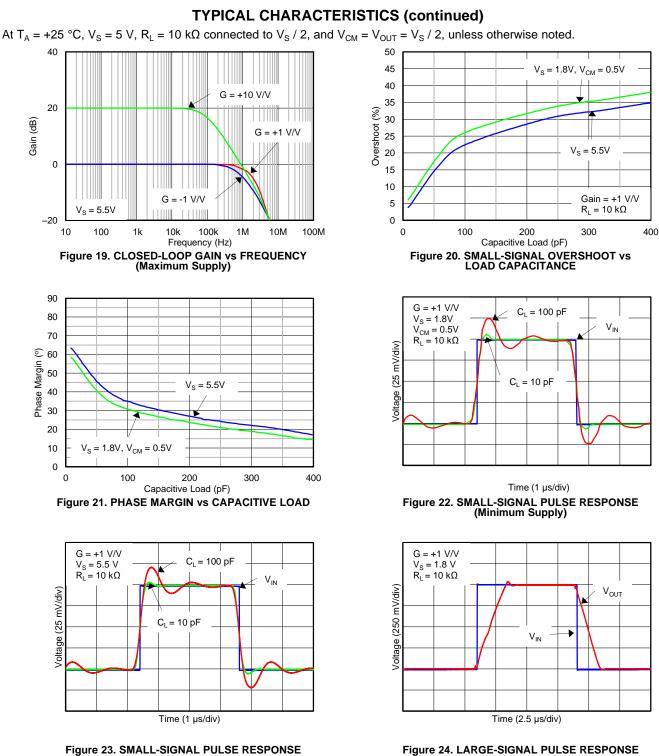


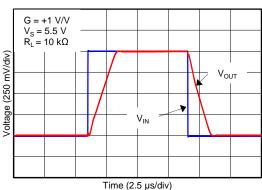
Figure 24. LARGE-SIGNAL PULSE RESPONSE (Minimum Supply)

(Maximum Supply)





At $T_A = +25$ °C, $V_S = 5$ V, $R_L = 10$ k Ω connected to V_S / 2, and $V_{CM} = V_{OUT} = V_S$ / 2, unless otherwise noted.



Time (2.5 µ5/div)



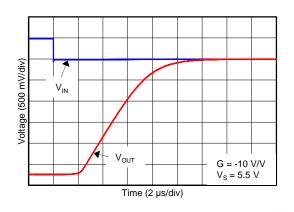
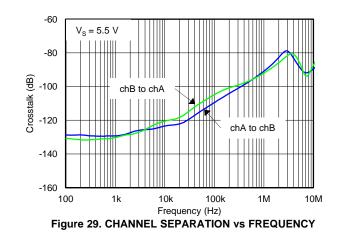


Figure 27. NEGATIVE OVERLOAD RECOVERY



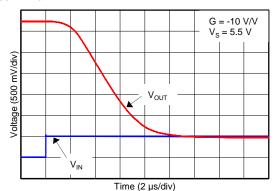


Figure 26. POSITIVE OVERLOAD RECOVERY

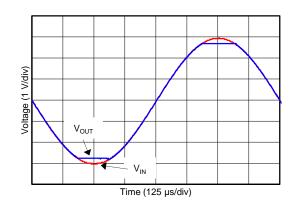
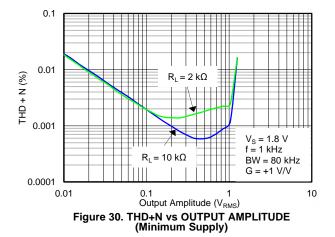
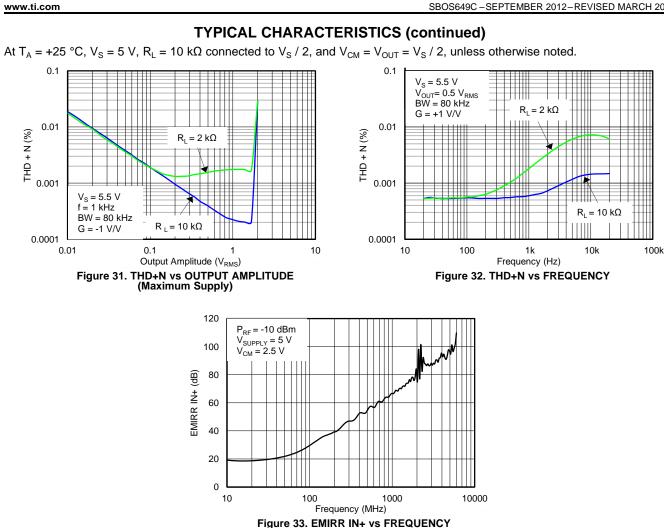


Figure 28. NO PHASE REVERSAL





OPA313 OPA2313 OPA4313 SBOS649C – SEPTEMBER 2012–REVISED MARCH 2013





APPLICATION INFORMATION

The OPA313 is a family of low-power, rail-to-rail input and output operational amplifiers specifically designed for portable applications. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving \leq 10-k Ω loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails, and allows the OPA313 family to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes them ideal for driving sampling analog-to-digital converters (ADCs).

The OPA313 features 1-MHz bandwidth and 0.5-V/ μ s slew rate with only 50- μ A supply current per channel, providing good ac performance at very low power consumption. DC applications are also well served with a low input noise voltage of 25 nV/ \sqrt{Hz} at 1 kHz, low input bias current (0.2 pA), and an input offset voltage of 0.5 mV (typical). The typical offset voltage drift is 2 μ V/°C; over the full temperature range the input offset voltage changes only 200 μ V (0.5 mV to 0.7 mV).

OPERATING VOLTAGE

The OPA313 series op amps are fully specified and ensured for operation from +1.8 V to +5.5 V. In addition, many specifications apply from -40° C to +125°C. Parameters that vary significantly with operating voltages or temperature are shown in the Typical Characteristics graphs. Power-supply pins should be bypassed with 0.01- μ F ceramic capacitors.

RAIL-TO-RAIL INPUT

The input common-mode voltage range of the OPA313 series extends 200 mV beyond the supply rails. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in Figure 34. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.3 V to 200 mV above the positive supply, while the P-channel pair is on for inputs from 200 mV below the negative supply to approximately (V+) - 1.3 V. There is a small transition region, typically (V+) - 1.4 V to (V+) - 1.2 V, in which both pairs are on. This 200-mV transition region can vary up to 300 mV with process variation. Thus, the transition region (both stages on) can range from (V+) - 1.7 V to (V+) - 1.5 V on the low end, up to (V+) - 1.1 V to (V+) - 0.9 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD may be degraded compared to device operation outside this region.

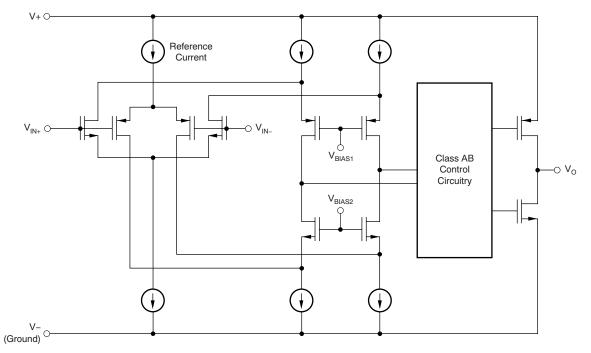


Figure 34. Simplified Schematic



INPUT AND ESD PROTECTION

The OPA313 family incorporates internal electrostatic discharge (ESD) protection circuits on all pins. In the case of input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes also provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA as stated in the Absolute Maximum Ratings. Figure 35 shows how a series input resistor may be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and its value should be kept to a minimum in noise-sensitive applications.

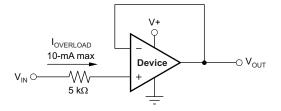


Figure 35. Input Current Protection

COMMON-MODE REJECTION RATIO (CMRR)

CMRR for the OPA313 is specified in several ways so the best match for a given application may be used; see the Electrical Characteristics. First, the CMRR of the device in the common-mode range below the transition region $[V_{CM} < (V+) - 1.3 V]$ is given. This specification is the best indicator of the capability of the device when the application requires use of one of the differential input pairs. Second, the CMRR over the entire common-mode range is specified at ($V_{CM} = -0.2 V$ to 5.7 V). This last value includes the variations seen through the transition region (see Figure 7).

EMI SUSCEPTIBILITY AND INPUT FILTERING

Operational amplifiers vary with regard to the susceptibility of the device to electromagnetic interference (EMI). If conducted EMI enters the op amp, the dc offset observed at the amplifier output may shift from its nominal value while EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. While all op amp pin functions can be affected by EMI, the signal input pins are likely to be the most susceptible. The OPA313 operational amplifier family incorporate an internal input low-pass filter that reduces the amplifiers response to EMI. Both common-mode and differential mode filtering are provided by this filter. The filter is designed for a cutoff frequency of approximately 35 MHz (–3 dB), with a roll-off of 20 dB per decade.

Texas Instruments has developed the ability to accurately measure and quantify the immunity of an operational amplifier over a broad frequency spectrum extending from 10 MHz to 6 GHz. The EMI rejection ratio (EMIRR) metric allows op amps to be directly compared by the EMI immunity. Figure 33 illustrates the results of this testing on the OPA313 family. Detailed information can also be found in the application report, *EMI Rejection Ratio of Operational Amplifiers* (SBOA128), available for download from www.ti.com.

RAIL-TO-RAIL OUTPUT

Designed as a micro-power, low-noise operational amplifier, the OPA313 delivers a robust output drive capability. A class AB output stage with common-source transistors is used to achieve full rail-to-rail output swing capability. For resistive loads up to 10 k Ω , the output swings typically to within 5 mV of either supply rail regardless of the power-supply voltage applied. Different load conditions change the ability of the amplifier to swing close to the rails; refer to the typical characteristic graph, *Output Voltage Swing vs Output Current*.



CAPACITIVE LOAD AND STABILITY

The OPA313 is designed to be used in applications where driving a capacitive load is required. As with all op amps, there may be specific instances where the OPA313 can become unstable. The particular op amp circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether or not an amplifier is stable in operation. An op amp in the unity-gain (+1-V/V) buffer configuration that drives a capacitive load exhibits a greater tendency to be unstable than an amplifier operated at a higher noise gain. The capacitive load, in conjunction with the op amp output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases as the capacitive load up to approximately 1 nF. The equivalent series resistance (ESR) of some very large capacitors (C_L greater than 1 μ F) is sufficient to alter the phase characteristics in the feedback loop such that the amplifier remains stable. Increasing the amplifier closed-loop gain allows the amplifier to drive increasingly larger capacitance. This increased capability is evident when observing the overshoot response of the amplifier at higher voltage gains. See the typical characteristic graph, *Small-Signal Overshoot vs. Capacitive Load*.

One technique for increasing the capacitive load drive capability of the amplifier operating in a unity-gain configuration is to insert a small resistor, typically 10 Ω to 20 Ω , in series with the output, as shown in Figure 36. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads. One possible problem with this technique, however, is that a voltage divider is created with the added series resistor and any resistor connected in parallel with the capacitive load. The voltage divider introduces a gain error at the output that reduces the output swing.

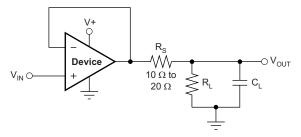


Figure 36. Improving Capacitive Load Drive

DFN PACKAGE

The OPA2313 (dual version) uses the DFN style package (also known as SON); this package is a QFN with contacts on only two sides of the package bottom. This leadless package maximizes printed circuit board (PCB) space and offers enhanced thermal and electrical characteristics through an exposed pad. One of the primary advantages of the DFN package is its low, 0.9-mm height. DFN packages are physically small, have a smaller routing area, improved thermal performance, reduced electrical parasitics, and use a pinout scheme that is consistent with other commonly-used packages, such as SO and MSOP. Additionally, the absence of external leads eliminates bent-lead issues.

The DFN package can easily be mounted using standard PCB assembly techniques. See Application Note, *QFN/SON PCB Attachment* (SLUA271) and Application Report, *Quad Flatpack No-Lead Logic Packages* (SCBA017), both available for download from www.ti.com.

NOTE

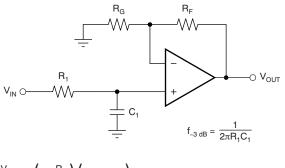
The exposed leadframe die pad on the bottom of the DFN package should be connected to the most negative potential (V–).



APPLICATION EXAMPLES

GENERAL CONFIGURATIONS

When receiving low-level signals, limiting the bandwidth of the incoming signals into the system is often required. The simplest way to establish this limited bandwidth is to place an RC filter at the noninverting terminal of the amplifier, as Figure 37 shows.



 $\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$

Figure 37. Single-Pole Low-Pass Filter

If even more attenuation is needed, a multiple pole filter is required. The Sallen-Key filter can be used for this task, as Figure 38 shows. For best results, the amplifier should have a bandwidth that is eight to 10 times the filter frequency bandwidth. Failure to follow this guideline can result in phase shift of the amplifier.

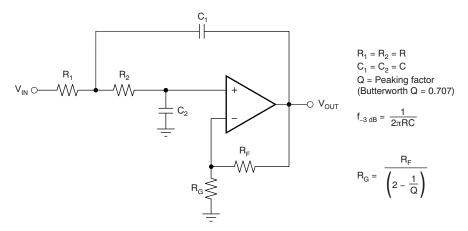


Figure 38. Two-Pole Low-Pass Sallen-Key Filter

Page

REVISION HISTORY

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision B (December 2012) to Revision C						
•	Changed first Open-Loop Gain, A _{OL} typical specification in Electrical Characteristics: +5.5 V table	3				
•	Updated Figure 10	11				
•	Updated Figure 19 through Figure 22	12				

Changes from Revision A (Sepetmber 2012) to Revision B

•	Changed title of document	1
•	Changed third paragraph of Description section	1
•	Changed title of Electrical Characteristics: +5.5 V table	3
•	Deleted middle two rows from Input Voltage Range, CMRR parameter in Electrical Characteristics: +5.5 V table	3
•	Changed test conditions of Input Voltage Range, CMRR parameter in Electrical Characteristics: +5.5 V table	3
•	Added footnote to Input Bias Current, I_B and I_{OS} parameters in Electrical Characteristics: +5.5 V table	3
•	Changed Open-Loop Gain, A _{OL} parameter in Electrical Characteristics: +5.5 V table	3
•	Deleted first row from Frequency Response, GBW parameter in Electrical Characteristics: +5.5 V table	4
•	Deleted first row from Frequency Response, SR parameter in Electrical Characteristics: +5.5 V table	4
•	Changed Output, V _o parameter in Electrical Characteristics: +5.5 V table	4
•	Changed Output, I _{SC} parameter in Electrical Characteristics: +5.5 V table	4
•	Changed test conditions for the first row in the Power Supply, I _Q parameter in Electrical Characteristics: +5.5 V table	4
•	Changed Electrical Characteristics: +1.8 V table	5
•	Changed conditions of Electrical Characteristics: +1.8 V table	5
•	Changed last row of Input Voltage Range, CMRR parameter in Electrical Characteristics: +1.8 V table	5
•	Changed footnote to Input Bias Current, I_B and I_{OS} parameters in Electrical Characteristics: +1.8 V table	5
•	Changed Open-Loop Gain, A _{OL} parameter in Electrical Characteristics: +1.8 V table	5
•	Changed Frequency Response, <i>GBW</i> parameter test conditions in Electrical Characteristics: +1.8 V table	6
•	Changed Frequency Response, SR parameter test conditions in Electrical Characteristics: +1.8 V table	6
•	Changed Output, V _o parameter test conditions in Electrical Characteristics: +1.8 V table	6
•	Changed Output, I _{SC} parameter in Electrical Characteristics: +1.8 V table	6
•	Deleted last row from Power Supply, I_Q parameter in Electrical Characteristics: +1.8 V table	6
•	Updated Figure 2	10

Changes from Original (September 2012) to Revision A

Page

Changed from product preview to production data



30-Jun-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
OPA2313ID	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	OP2313	Samples
OPA2313IDGK	ACTIVE	VSSOP	DGK	8	80	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	OUSS	Samples
OPA2313IDGKR	ACTIVE	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	OUSS	Samples
OPA2313IDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	OP2313	Samples
OPA2313IDRGR	ACTIVE	SON	DRG	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	SDY	Samples
OPA2313IDRGT	ACTIVE	SON	DRG	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	SDY	Samples
OPA313IDBVR	ACTIVE	SOT-23	DBV	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	SIE	Samples
OPA313IDBVT	ACTIVE	SOT-23	DBV	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	SIE	Samples
OPA313IDCKR	ACTIVE	SC70	DCK	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	SIF	Samples
OPA313IDCKT	ACTIVE	SC70	DCK	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	SIF	Samples
OPA4313IPW	ACTIVE	TSSOP	PW	14	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	OPA4313	Samples
OPA4313IPWR	ACTIVE	TSSOP	PW	14	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	OPA4313	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.



30-Jun-2013

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



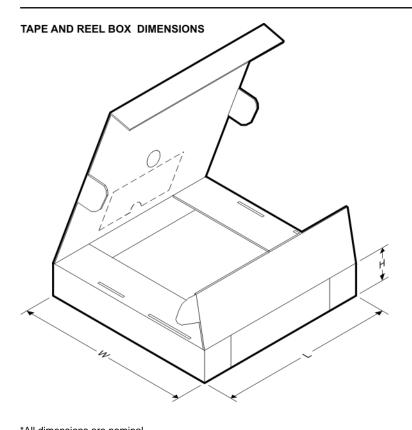
*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
OPA2313IDGKR	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
OPA2313IDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
OPA2313IDRGR	SON	DRG	8	3000	330.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
OPA2313IDRGT	SON	DRG	8	250	180.0	12.4	3.3	3.3	1.1	8.0	12.0	Q2
OPA313IDBVR	SOT-23	DBV	5	3000	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
OPA313IDBVT	SOT-23	DBV	5	250	178.0	9.0	3.23	3.17	1.37	4.0	8.0	Q3
OPA313IDCKR	SC70	DCK	5	3000	178.0	9.0	2.4	2.5	1.2	4.0	8.0	Q3
OPA4313IPWR	TSSOP	PW	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

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PACKAGE MATERIALS INFORMATION

2-May-2014



*All dimensions are nominal							
Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
OPA2313IDGKR	VSSOP	DGK	8	2500	366.0	364.0	50.0
OPA2313IDR	SOIC	D	8	2500	340.5	338.1	20.6
OPA2313IDRGR	SON	DRG	8	3000	367.0	367.0	35.0
OPA2313IDRGT	SON	DRG	8	250	210.0	185.0	35.0
OPA313IDBVR	SOT-23	DBV	5	3000	180.0	180.0	18.0
OPA313IDBVT	SOT-23	DBV	5	250	180.0	180.0	18.0
OPA313IDCKR	SC70	DCK	5	3000	180.0	180.0	18.0
OPA4313IPWR	TSSOP	PW	14	2000	367.0	367.0	35.0

DCK (R-PDSO-G5)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES: A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
 - D. Falls within JEDEC MO-203 variation AA.



LAND PATTERN DATA



NOTES:

- A. All linear dimensions are in millimeters.B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



DBV 5

GENERIC PACKAGE VIEW

SOT-23 - 1.45 mm max height SMALL OUTLINE TRANSISTOR



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 Reference JEDEC MO-178.



EXAMPLE BOARD LAYOUT

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

4. Publication IPC-7351 may have alternate designs.

5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



EXAMPLE STENCIL DESIGN

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

7. Board assembly site may have different recommendations for stencil design.



^{6.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.



PACKAGE OUTLINE

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
 This drawing is subject to change without notice.
 Reference JEDEC MO-178.



EXAMPLE BOARD LAYOUT

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

4. Publication IPC-7351 may have alternate designs.

5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



EXAMPLE STENCIL DESIGN

SOT-23 - 1.45 mm max height

SMALL OUTLINE TRANSISTOR



NOTES: (continued)

7. Board assembly site may have different recommendations for stencil design.



^{6.} Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

PW (R-PDSO-G14)

PLASTIC SMALL OUTLINE



A. An integration of the information o

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.

- D Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



DGK (S-PDSO-G8)

PLASTIC SMALL OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



MECHANICAL DATA



E. JEDEC MO-229 package registration pending.



DRG (S-PWSON-N8)

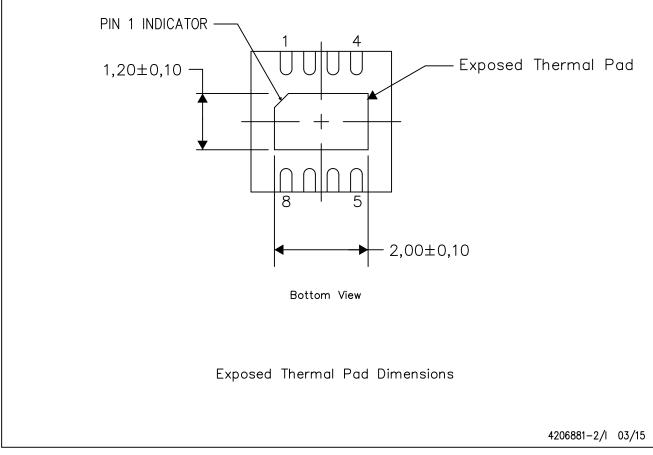
PLASTIC SMALL OUTLINE NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

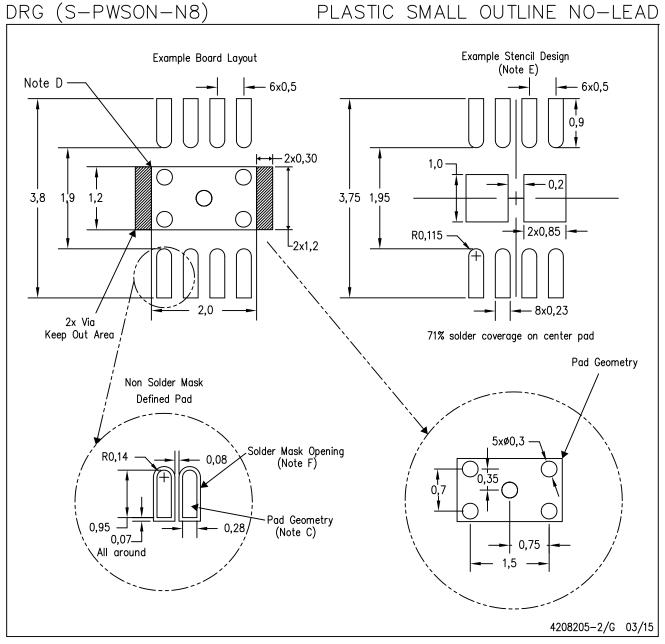
For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.









NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-SM-782 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.



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